





COMPLEMENTARY SILICON PLANAR EPITAXIAL TRANSISTORS

CSA1020 PNP CSC2655 NPN



TO-92

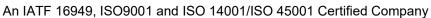
TO-92 Leaded Plastic Package RoHS compliant

ABSOLUTE MAXIMUM RATINGS (Ta = 25 °C Unless otherwise specified)

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PARAMETER	SYMBOL	VALUE	UNIT
Collector Emitter Voltage	V_{CEO}	50	V
Collector Base Voltage	V_{CBO}	50	V
Emitter Base Voltage	V_{EBO}	5	V
Collector Current	I _C	2	Α
Collector Power Dissipation	P _c	900	mW
Operating And Storage Junction Temperature Range	T_{j},T_{stg}	-50 to 150	°C



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ELECTRICAL CHARACTERISTICS* at (Ta = 25 °C Unless otherwise specified)

PARAMETER		SYMBOL TEST CONDITION		VALUE			UNIT
				MIN	TYP	MAX	CINIT
Collector Emitter Voltage		BV_CEO	$I_C=10mA,I_B=0$	50.00			V
Collector Cut off Current		I _{CBO}	$V_{CB} = 50V, I_{E} = 0$		-	1	μΑ
Emitter Cut off Current		I _{EBO}	$V_{EB}=5V$, $I_C=0$			1	μA
DC Current Coin		h _{FE}	V_{CE} =2V, I_{C} =500mA	70		240	
DC Current Gain	DC Current Gain		$V_{CE}=2V,I_{C}=1.5A$	40			
Collector Emitter Saturation Voltage		V _{CE(sat)}	I _C =1A, I _B =50mA		-	0.5	V
Base Emitter Saturation Voltage		$V_{BE(sat)}$	I _C =1A, I _B =50mA			1.2	V
DYNAMIC CHARACTERISTICS							
Gain Bandwidth Product		f_T	I_C =500mA, V_{CE} =2V		100		MHz
Output Capacitance PNP NPN		C	I _E =0, V _{CB} =10V,f=1MHz		40	-	pF
		C_ob	1 _E -0, v _{CB} -10v,1-1101112		30		рF
Switching Time							
Turn on Time		t _{on}	\\ -30\\ - - 50m \		0.1		
Storage Time		t _{stg}	V_{CC} =30V, I_{B1} = I_{B2} = 50mA, R_1 =30Ω, Duty Cycle=1%		1	-	μs
Fall Time		t _f	N _L -3022, Duty Cycle-1%		0.1		

Notes:

1. Pulse test.

h_{FE} Classifications

0	Y
70 ~140	120 ~240



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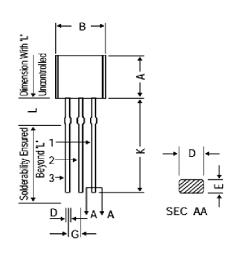




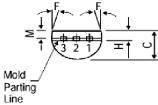


PACKAGE DETAILS

TO-92 Leaded Plastic Package



o i donago					
MIN	MAX				
4.32	5.33				
4.45	5.20				
3.18	4.19				
0.41	0.55				
0.35	0.50				
5 DEG					
1.14	1.40				
1.20	1.40				
12.7					
1.982	2.082				
1.03	1.20				
	4.32 4.45 3.18 0.41 0.35 5 E 1.14 1.20 12.7 1.982				

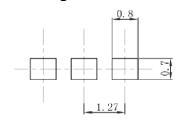


All Dimensions are in mm

Pin Configuration

- 1. Base
- 2. Collector
- 3. Emitter

PCB Design:



Note:

- 1. Controlling dimension in mm.
- 2.General tolerance:±0.05mm.
- 3. The pad layout is for reference purposes only.

Unit:mm

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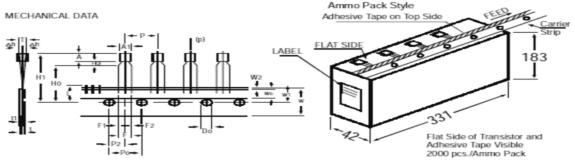
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TO-92 Transistors on Tape and Ammo Pack



All dimensions in mm unless specified otherwise

ITEM			SPECIF	ICATIO	N	
ITEM	SYMBOL	MIN.	NOM.	MAX.	TOL.	REMARKS
BODY WIDTH BODY HEIGHT BODY THICKNESS PITCH OF COMPONENT FEED HOLE PITCH	A1 A T P	4.0 4.8 3.9	12.7 12.7	4.8 5.2 4.2	±1 ±0.3	CUMULATIVE PITCH ERROR 1.0 mm/20
FEED HOLE CENTRE TO COMPONENT CENTRE	P2		6.35		±0.4	PITCH TO BE MEASURED AT BOTTOM OF CLINCH
DISTANCE BETWEEN OUTER LEADS COMPONENT ALIGNMENT TAPE WIDTH HOLD-DOWN TAPE WIDTH HOLE POSITION	F △h W Wo W1		5.08 0 18 6 9	1	+0.6 -0.2 ±0.5 ±0.2 +0.7 -0.5	AT TOP OF BODY
HOLD-DOWN TAPE POSITION LEAD WIRE CLINCH HEIGHT COMPONENT HEIGHT LENGTH OF SNIPPED LEADS FEED HOLE DIAMETER TOTAL TAPE THICKNESS LEAD - TO - LEAD DISTANCEF1,	W2 Ho H1 L Do t		0.5 16 4 2.54	23.25 11.0 1.2	±0.2 ±0.5 ±0.2 +0.4	t1 0.3 - 0.6
CLINCH HEIGHT PULL - OUT FORCE	H2 (P)	6N		3	-0.1	

NOTES

- 1. MAXIMUM ALIGNMENT DEVIATION BETWEEN LEADS NOT TO BE GREATER THAN 0.2 mm.
- 2. MAXIMUM NON-CUMULATIVE VARIATION BETWEEN TAPE FEED HOLES SHALL NOT EXCEED 1 mm IN 20 PITCHES.
- 3. HOLDDOWN TAPE NOT TO EXCEED BEYOND THE EDGE(S) OF CARRIER TAPE AND THERE SHALL BE NO EXPOSURE OF ADHESIVE.
- 4. NO MORE THAN 3 CONSECUTIVE MISSING COMPONENTS ARE PERMITTED.
- 5. A TAPE TRAILER, HAVING AT LEAST THREE FEED HOLES ARE REQUIRED AFTER THE LAST COMPONENT.
- 6. SPLICES SHALL NOT INTERFERE WITH THE SPROCKET FEED HOLES.

Packing Detail

PACKAGE	STANDARD PACK		INNER CARTON BOX		OUTER CARTON BOX		
	Details	Net Weight/Qty	Size	Qty	Size	Qty	Gr Wt
TO-92 Bulk	1K/polybag	200 gm/1K pcs	3" x 7.5" x 7.5"	5K	17" x 15" x 13.5"	80K	23 kgs
TO-92 T&A	2K/ammo box	645 gm/2K pcs	12.5" x 8" x 1.8"	2K	17" x 15" x 13.5"	32K	12.5 kgs

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Recommended Reflow Solder Profiles

The recommended reflow solder profiles for Pb and Pb-free devices are shown below.

Figure 1 shows the recommended solder profile for devices that have Pb-free terminal plating, and where a Pb-free solder is used.

Figure 2 shows the recommended solder profile for devices with Pb-free terminal plating used with leaded solder, or for devices with leaded terminal plating used with a leaded solder.

Figure 1

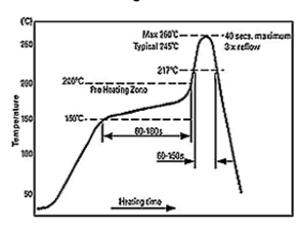
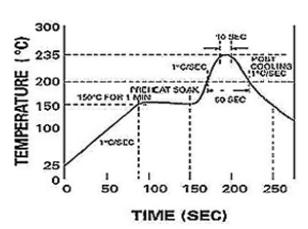


Figure 2



Reflow profiles in tabular form

Profile Feature	Sn-Pb System	Pb-Free System
Average Ramp-Up Rate	~3°C/second	~3°C/second
Preheat		
– Temperature Range	150-170°C	150-200°C
– Time	60-180 seconds	60-180 seconds
Time maintained above:		
Temperature	200°C	217°C
– Time	30-50 seconds	60-150 seconds
Peak Temperature	235°C	260°C max.
Time within +0 -5°C of actual Peak	10 seconds	40 seconds
Ramp-Down Rate	3°C/second max.	6°C/second max.

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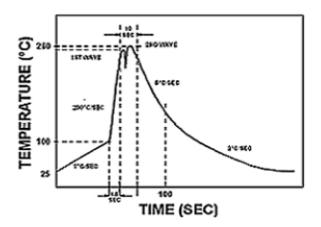




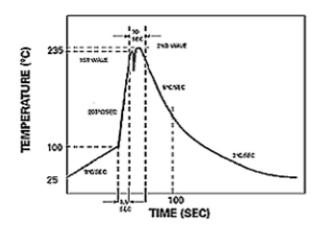


Recommended Wave Solder Profiles

The Recommended solder Profile For Devices with Pb-free terminal plating where a Pb-free solder is used



The Recommended solder Profile For Devices with Pb-free terminal plating used with leaded solder, or for devices with leaded terminal plating used with leaded solder



Wave Profiles in Tabular Form

Profile Feature	Sn-Pb System	Pb-Free System
Average Ramp-Up Rate	~200°C/second	~200°C/second
Heating rate during preheat	Typical 1-2, Max 4°C/sec	Typical 1-2, Max 4°C/Sec
Final preheat Temperature	Within 125°C of Solder Temp	Within 125°C of Solder Temp
Peak Temperature	235°C	260°C max.
Time within +0 -5°C of actual Peak	10 seconds	10 seconds
Ramp-Down Rate	5°C/second max.	5°C/second max





Recommended Product Storage Environment for Discrete Semiconductor Devices

This storage environment assumes that the Diodes and transistors are packed properly inside the original packing supplied by CDIL.

- · Temperature 5 °C to 30 °C
- · Humidity between 40 to 70 %RH
- · Air should be clean.
- · Avoid harmful gas or dust.
- · Avoid outdoor exposure or storage in areas subject to rain or water spraying .
- · Avoid storage in areas subject to corrosive gas or dust. Product shall not be stored in areas exposed to direct sunlight.
- · Avoid rapid change of temperature.
- · Avoid condensation.
- · Mechanical stress such as vibration and impact shall be avoided.
- · The product shall not be placed directly on the floor.
- The product shall be stored on a plane area. They should not be turned upside down. They should not be placed against the wall.

Shelf Life of CDIL Products

The shelf life of products is the period from product manufacture to shipment to customers. The product can be unconditionally shipped within this period. The period is defined as 2 years.

If products are stored longer than the shelf life of 2 years the products shall be subjected to quality check as per CDIL quality procedure.

The products are further warranted for another one year after the date of shipment subject to the above conditions in CDIL original packing.

Floor Life of CDIL Products and MSL Level

When the products are opened from the original packing, the floor life will start.

For this, the following JEDEC table may be referred:

JEDEC MSL Level					
Level	Time	Condition			
1	Unlimited	≤30 °C / 85% RH			
2	1 Year	≤30 °C / 60% RH			
2a	4 Weeks	≤30 °C / 60% RH			
3	168 Hours	≤30 °C / 60% RH			
4	72 Hours	≤30 °C / 60% RH			
5	48 Hours	≤30 °C / 60% RH			
5a	24 Hours	≤30 °C / 60% RH			
6	Time on Label(TOL)	≤30 °C / 60% RH			

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Customer Notes

Component Disposal Instructions

- 1. CDIL Semiconductor Devices are RoHS compliant, customers are requested to please dispose as per prevailing Environmental Legislation of their Country.
- 2. In Europe, please dispose as per EU Directive 2002/96/EC on Waste Electrical and Electronic Equipment (WEEE).

Disclaimer

The product information and the selection guides facilitate selection of the CDIL's Semiconductor Device(s) best suited for application in your product(s) as per your requirement. It is recommended that you completely review our Data Sheet(s) so as to confirm that the Device(s) meet functionality parameters for your application. The information furnished in the Data Sheet and on the CDIL Web Site/CD are believed to be accurate and reliable. CDIL however, does not assume responsibility for inaccuracies or incomplete information. Furthermore, CDIL does not assume liability whatsoever, arising out of the application or use of any CDIL product; neither does it convey any license under its patent rights nor rights of others. These products are not designed for use in life saving/support appliances or systems. CDIL customers selling these products (either as individual Semiconductor Devices or incorporated in their end products), in any life saving/support appliances or systems or applications do so at their own risk and CDIL will not be responsible for any damages resulting from such sale(s).

CDIL strives for continuous improvement and reserves the right to change the specifications of its products without prior notice.



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